

TUZ 2023

Call for Papers



Erfurt, 26th to 28th February 2023

35. ITG / GMM / GI - Workshop on Test Methods and Reliability of Circuits and Systems

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The Workshop on Test Methods and Reliability of Circuits and Systems is the most significant German forum to discuss trends, results and current problems in the area of test, diagnosis and reliability of digital, analog, mixed-signal and high-frequency-circuits. The exchange of ideas is an important intention of this workshop. The scope includes contributions discussing industrial practice as well as research. We strongly welcome practice-related technical reports and results as well as contributions presenting theoretical work from the following areas:

- Adaptive systems (e.g. self-repair, self-healing, self-awareness)
- Automatic test equipment, test automation, test programs and test modelling
- Defect and failure modeling
- Diagnosis of failure causes
- Fault tolerance, resilience, robust and radiation-resistant systems
- Functional safety
- Hardware-oriented test and hardware-oriented safety
- Statistical and machine learning techniques for test and reliability
- System test and reliability
- Test and simulation of mixed-signal, RF and analog circuits
- Test generation, fault simulation, self-test and online-test
- Design-For-Test, DFT methodology
- Test costs and test quality
- Test standards such as IEEE 1149.x, IEEE 1687.x, IEEE P1838

The workshop takes place in the Victor's Residenz-Hotel in Erfurt, Germany, and is organized by the University of Applied Sciences Nordhausen and the University of Applied Sciences Hamm-Lippstadt. Interested contributors should summarize their work onto no more than 2 pages, which can be submitted via the workshop-website. The contribution should describe the purpose, the novelty and practical applications of the work. Accepted papers can be published in the informal workshop handout, if requested. For this purpose, the contribution could be extended to 4 pages.



Workshop-Homepage

www.tuz-workshop.de

Submission-Site

<https://easychair.org/conferences/?conf=tuz23>

Important Dates

Deadline for paper submission: ~~06.~~ **20. Nov. 2022**

Notification of acceptance: 18. Dec. 2022

Camera-ready-paper: 18. Jan. 2023

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GMM

VDE ITG